

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			09/502,675	Yamazaki et al.	
Examiner			Art Unit	2813	Page 1 of 1
Evan T. Pert					

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
X	A	US-6,127,210	10-2000	Mimura et al.	--	--
X	B	US-5,706,064	01-1998	Fukunaga et al.	--	--
X	C	US-5,499,123	03-1996	Mikoshiba	--	--
X	D	US-5,302,966	04-1994	Stewart	--	--
	E	US-				
	F	US-				
	G	US-				
	H	US-				
	I	US-				
	J	US-				
	K	US-				
	L	US-				
	M	US-				

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
X	U	Hatano et al. "A NOVEL Self-aligned Gate-overlapped LDD poly-Si TFT with High Reliability and Performance", 1997, IEEE, IEDM, pages 523-526.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.